WMSC006H12B2S

N-Channel Silicon Carbide MOSFET Module

Rev.03 - 24 September 2024

Product data sheet

1. General description

WeEnPACK-B2 module with WeEn 1200V Gen2 SiC MOSFET and Solder pin type. Integrated with NTC temperature sensor.



2. Features and benefits

- · Half bridge topology
- Solder pin configuration
- Low R_{DSon}-T_j coefficient
- Low Switching Losses
- Low Q_a and C_{rss}
- Mimimized circuit impedance
- Improved chip synchronization performance

3. Applications

- Power inverters
- AC-DC converters
- DC-DC converters
- · Active power factor correctors
- Motor drives

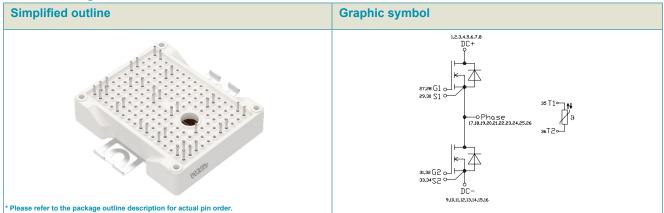
4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Notes	Values			Unit
Absolute	maximum rating						
V _{DS}	drain-source voltage	T _j = 25 °C			1200		V
I _D	drain current	V _{GS} = 15 V; T _h = 25 °C			200		Α
P _{tot}	total power dissipation	T _h = 25 °C			278		W
$T_{j.op}$	operating junction temperature				-40 to 15	0	°C
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static ch	aracteristics						
R _{DS(on)}	drain-source on-state resistance	$V_{GS} = 15 \text{ V}; I_D = 200 \text{ A}; T_j = 25 \text{ °C}$		-	6.0	-	mΩ
		V _{GS} = 18 V; I _D = 200 A; T _j = 25 °C		-	5.0	10	mΩ
Dynamic	characteristics						
Q _{G(tot)}	total gate charge	$I_D = 200 \text{ A}; V_{DS} = 800 \text{ V}; V_{GS} = 0 \text{ V}/18 \text{ V};$		-	651	-	nC
Q_{GD}	gate-drain charge	T _j = 25 °C		-	119	-	nC
Source-d	rain diode						
Q_r	recovered charge	I_{SD} = 200 A; V_{GS} = -4 V/18 V; V_{R} = 600 V; di/dt =3100 A/µs;		-	1337	-	nC

5. Pinning information

Table 2. Pinning information



6. Ordering information

Table 3. Ordering information

Type number	Package Name	Orderable part number	Packing method	Small packing quantity	. •	Package issue date
WMSC006H12B2S	WeEnPACK-B2	WMSC006H12B2S6T	Tray	12	WeEnPACK- B2PHB-A	31-Jan-2024

7. Marking

Table 4. Marking codes

Type number	Marking codes
WMSC006H12B2S	WMSC006H12B2S

8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Notes	Values	Unit
T _{stg}	storage temperature			-40 to 125	°C
$T_{j.op}$	operating junction temperature			-40 to 150	°C
$T_{j.max}$	maximum junction temperature	Intermittent condition with shortened lifetime		-40 to 175	°C
V _{ISOL}	RMS isolation voltage	T _j = 25 °C; all terminals shorted; f = 50 Hz; t = 1 s		3500	V
MOSFET					
V_{DS}	drain-source voltage	T _j = 25 °C		1200	V
$V_{GS,max}$	gate-source voltage	Absolute maximum values		-12 to 24	V
$V_{GS,op}$	gate-source voltage	Recommended operational values		-4 to 18	V
P _{tot}	total power dissipation	T _h = 25 °C		278	W
I _D	drain current	V _{GS} = 18 V; T _h = 25 °C		200	Α
		V _{GS} = 18 V; T _h = 100 °C		126	Α
I _{DM}	peak drain current	pulsed; $t_p \le 10 \ \mu s$; $T_h = 25 \ ^{\circ}C$		450	Α
E _{as}	single pulse drain-to- source avalanche	I_{AS} = 20 A; L = 1 mH; V_{DD} = 100 V; $T_{j(init)}$ = 25 °C; per MOSFET		200	mJ
Body Diod	de				
I _{SD}	DC body diode forward current	T _h = 25 °C; V _{GS} = -4 V		70	Α
I _{SD,pulse}	Pulse body diode current	verified by design, t_p limited by T_{jmax}		450	Α

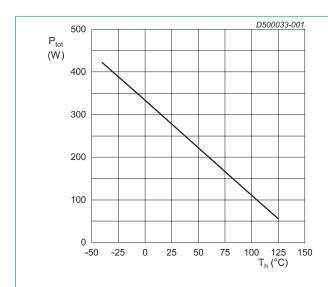


Fig. 1. Power dissipation as a function of heatsink temperature; maximum values

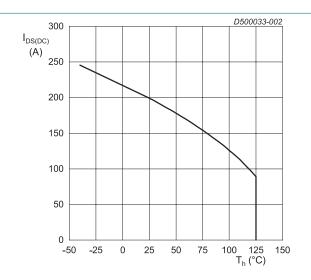


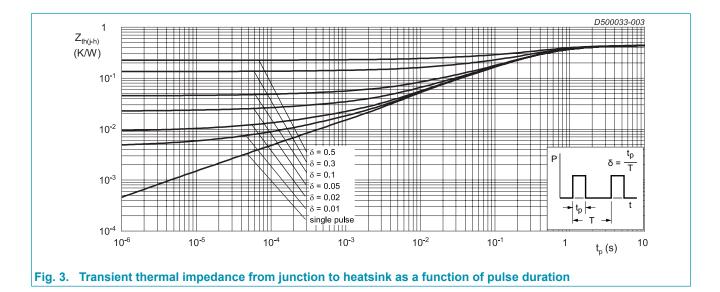
Fig. 2. Continuous Drain Current as a function of heatsink temperature

9. Thermal characteristics

Table 6. Thermal characteristics

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
R _{th(j-c)}	thermal resistance from junction to case	per MOSFET		-	0.125	-	K/W
R _{th(j-h)}	thermal resistance from junction to heatsink	per MOSFET, $\lambda_{grease} = 3 \text{ W/(m·K)}$, thick _{grease} = 50 um		-	0.45	-	K/W
Internal Is	solation	basic insulation (class 1, IEC 61140)			Al_2O_3		
d _{Creep}	Creepage distance	terminal to heatsink		-	11.5	-	mm
		terminal to terminal		-	6.3	-	mm
d _{Clear}	Clearance	terminal to heatsink		-	10	-	mm
		terminal to terminal		-	5	-	mm
CTI	Comperative tracking index				>200		
F	Mounting force per clamp			40	-	80	N
G	Approximate Weight			-	36	-	g

Note: Module is ESD sensitive. Handling precautions are recommended.



10. Characteristics

Table 7. Characteristics

MOSFET							
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static ch	aracteristics						
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 500 \mu A; V_{GS} = 0 V; T_j = 25 °C$		1200	-	-	V
$V_{\rm GS(th)}$	gate-source threshold	$I_D = 50 \text{ mA}; V_{DS} = 10 \text{ V}; T_j = 25 \text{ °C}$		1.9	2.5	3.5	V
	voltage	I _D = 50 mA; V _{DS} = 10 V; T _j = 175 °C		-	1.9	-	V
I _{DSS}	drain leakage current	V _{DS} = 1200 V; V _{GS} = 0 V; T _j = 25 °C		-	1	500	μA
I _{GSS}	gate leakage current	V _{GS} = 24 V; V _{DS} = 0 V; T _j = 25 °C		-	50	500	nA
	(absolute value)	V _{GS} = -12 V; V _{DS} = 0 V; T _j = 25 °C		-	50	500	nA
R _{DS(on)}	drain-source on-state	V _{GS} = 15 V; I _D = 200 A; T _j = 25 °C		-	6.0	-	mΩ
	resistance	V _{GS} = 18 V; I _D = 200 A; T _j = 25 °C		-	5.0	10	mΩ
		V _{GS} = 18 V; I _D = 200 A; T _j = 125 °C		-	6.4	-	mΩ
		V _{GS} = 18 V; I _D = 200 A; T _j = 150 °C		-	7.3	-	mΩ
	V _{GS} = 18 V; I _D = 200 A; T _j = 175 °C		-	7.7	-	mΩ	
R _G	gate resistance	f = 1 MHz; T _j = 25 °C; per MOSFET		-	0.99	-	Ω
g _{fs}	transconductance	V _{DS} = 20 V; I _D = 200 A; T _j = 25 °C		-	80	-	S
Dynamic	characteristics		'				
Q _{G(tot)}	total gate charge	I _D = 200 A; V _{DS} = 800 V; V _{GS} = 0 V/18 V;		-	651	-	nC
Q _{GS}	gate-source charge	T _j = 25 °C		-	212	-	nC
Q_{GD}	gate-drain charge			-	119	-	nC
C _{iss}	input capacitance	V _{DS} = 1000 V; V _{GS} = 0 V; f = 100 KHz;		-	16.5	-	nF
C _{oss}	output capacitance	T _j = 25 °C		-	758	-	pF
C _{rss}	reverse transfer capacitance			-	41	-	pF
E _{oss}	Coss stored energy			-	379	-	μJ
$t_{d(on)}$	turn-on delay time	V _{DS} = 800 V; V _{GS} = -4 V/18 V;		-	49	-	ns
t _r	rise time	$R_{G(off)} = 3.0 \ \Omega; \ R_{G(on)} = 3.0 \ \Omega;$ $I_D = 200 \ A; \ L = 100 \ \mu H; \ T_i = 25 \ ^{\circ}C$		-	36	-	ns
$t_{d(off)}$	turn-off delay time			-	162	-	ns
t _f	fall time			-	32	-	ns
E _{on}	turn-on energy			-	6.8	-	mJ
E _{off}	turn-off energy			-	3.8	-	mJ

Body dic	ode						
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static ch	aracteristics		,				
V_{SD}	source-drain voltage	$V_{GS} = -4 \text{ V}; I_{SD} = 200 \text{ A}; T_j = 25 \text{ °C}$		-	5.8	-	V
		$V_{GS} = -4 \text{ V}; I_{SD} = 200 \text{ A}; T_j = 150 \text{ °C}$		-	5.2	-	V
Dynamic	characteristics					•	
I _{rrm}	reverse recovery current	$I_{SD} = 200 \text{ A}; V_{GS} = -4 \text{ V}/18 \text{ V}; V_{R} = 600 \text{ V};$		-	73	-	Α
t _{rr}	reverse recovery time	di/dt = 3100 A/μs; $R_{G(ext)}$ = 5.1 Ω; T_i = 25 °C		-	33	-	ns
Q _r	recovered charge	J		-	1337	-	nC
E _{rec}	reverse recovery energy			-	102	-	μJ
NTC ther	mistor					1	
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
R ₂₅	Rated resistance	T _{NTC} = 25 °C		-	5000	-	Ω
R ₁₀₀		T _{NTC} = 100 °C			493±5%)	Ω
B _{25/50}	B-value	$R_2 = R_{25} \exp[B_{25/50}(1/T_2 - 1/(298.15K))]$		3380		K	
	Maximum operating temperature			-	200	-	°C
	Dissipation costant			-	2	-	mW/K
	Thermal time constant			-	≤10	-	S

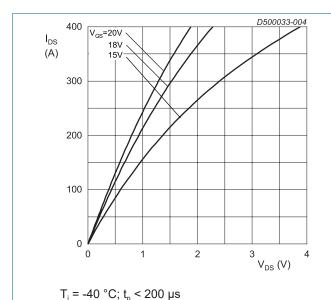
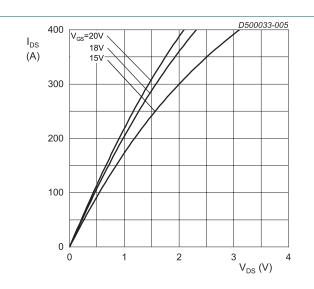
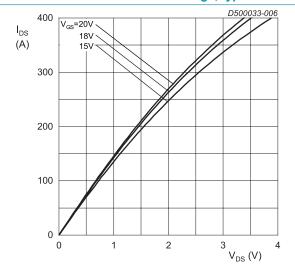


Fig. 4. Output characteristics; drain current as a function of drain-source voltage; typical values

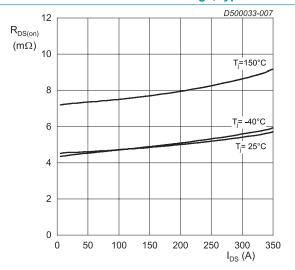


 $T_j = 25 \text{ °C}; t_p < 200 \text{ }\mu\text{s}$ Fig. 5. Output characteristics; drain cu

Fig. 5. Output characteristics; drain current as a function of drain-source voltage; typical values

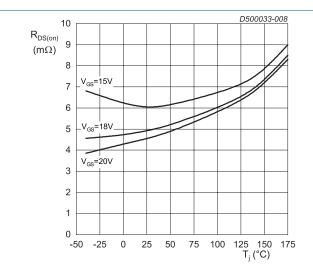


 $T_{j} = 150~^{\circ}\text{C}; \, t_{p} < 200~\mu\text{s}$ Fig. 6. Output characteristics; drain current as a function of drain-source voltage; typical values



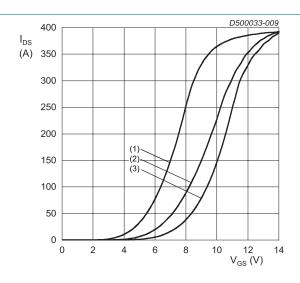
 $V_{GS} = 18 \text{ V}; t_p < 200 \text{ }\mu\text{s}$

Fig. 7. Drain-source on-state resistance as a function of drain current; typical values



 I_{DS} = 200 A; t_p < 200 μs

Fig. 8. Drain-source on-state resistance as a function of junction temperature



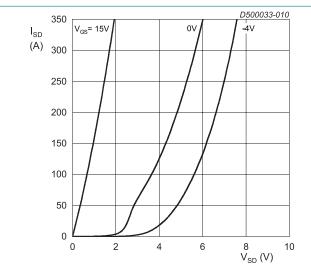
 V_{DS} = 20 V; t_p < 200 μs

 $(1)^{3}T_{i} = 150^{\circ}C$

(2) $T_j = 25 \,^{\circ}\text{C}$

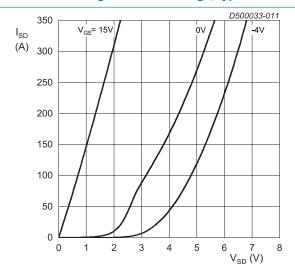
 $(3) T_{j} = -40 ^{\circ}C$

Fig. 9. Transfer characteristics; drain current as a function of gate-source voltage; typical values



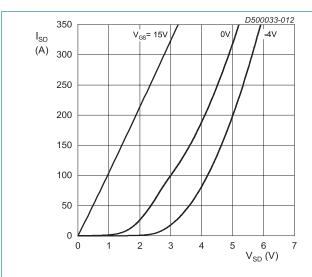
 $T_{\rm j}$ = -40 °C; $t_{\rm p}$ < 200 µs Fig. 10. Body diode forward characteristics;

typical values



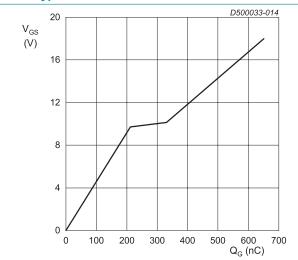
 $T_{\rm j}$ = 25 °C; $t_{\rm p}$ < 200 μs Fig. 11. Body diode forward characteristics;

Fig. 11. Body diode forward characteristics typical values

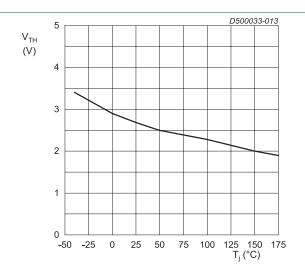


 $T_{\rm j}$ = 150 °C; $t_{\rm p}$ < 200 µs

Fig. 12. Body diode forward characteristics; typical values



 I_{DS} = 200 A; I_{GS} = 1 mA; V_{DS} = 800 V; T_j = 25 °C Fig. 14. Gate-source voltage as a function of gate charge; typical values



V_{DS} = 10 V; I_{DS} = 50 mA Fig. 13. Threshold voltage as a function of junction temperature

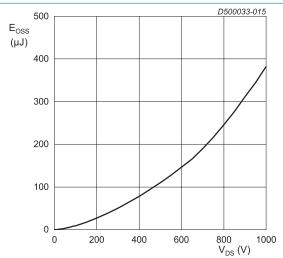
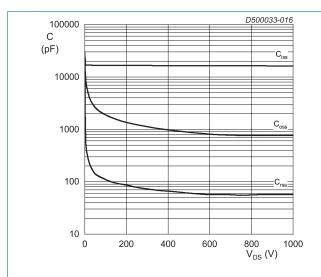
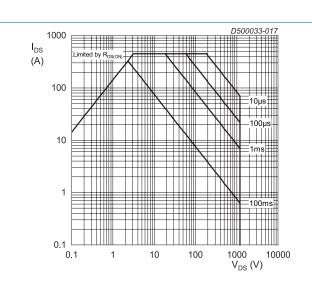


Fig. 15. Output capacitor stored energy as a function of drain-source voltage



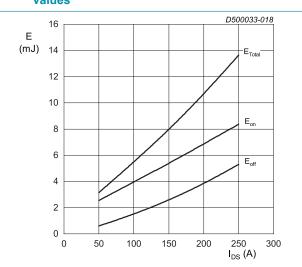
 $V_{DS} = 0 - 1000 \text{ V}$ $T_i = 25 \text{ °C}; V_{AC} = 25 \text{ mV}; f = 100 \text{ KHz}$

Fig. 16. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical values



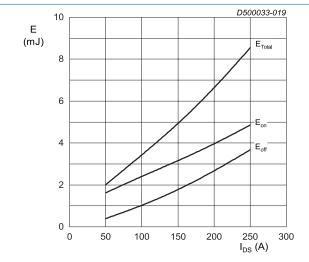
 $T_j = 25 \,^{\circ}\text{C}; D = 0$ Parameter: t_D

Fig. 17. Forward bias safe operating area



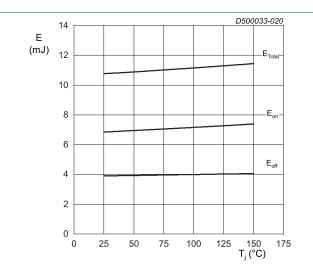
 $T_j = 25$ °C; $V_{DD} = 800$ V; $R_{G(off)} = 3.0$ Ω ; $R_{G(on)} = 3.0$ Ω ; $V_{GS} = -4$ V/18 V; L = 100 μ H

Fig. 18. Clamped Inductive Switching Energy as a function of drain current



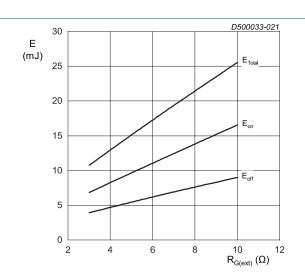
 T_{j} = 25 °C; V_{DD} = 600 V; $R_{G(off)}$ = 3.0 $\Omega;$ $R_{G(on)}$ = 3.0 $\Omega;$ V_{GS} = -4 V/18 V; L = 100 μH

Fig. 19. Clamped Inductive Switching Energy as a function of drain current



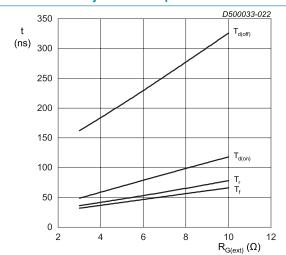
 I_{DS} = 200 A; V_{DD} = 800 V; $R_{G(off)}$ = 3.0 $\Omega;$ $R_{G(on)}$ = 3.0 $\Omega;$ V_{GS} = -4 V/18 V; L = 100 μH

Fig. 20. Clamped Inductive Switching Energy as a function of junction temperature



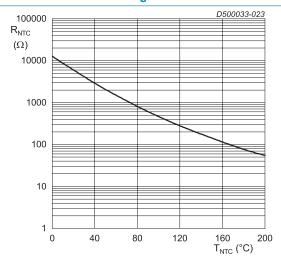
 T_j = 25 °C; V_{DD} = 800 V; I_{DS} = 200 A; V_{GS} = -4 V/18 V; $L = 100 \mu H$

Fig. 21. Clamped Inductive Switching Energy as a function of external gate resistance



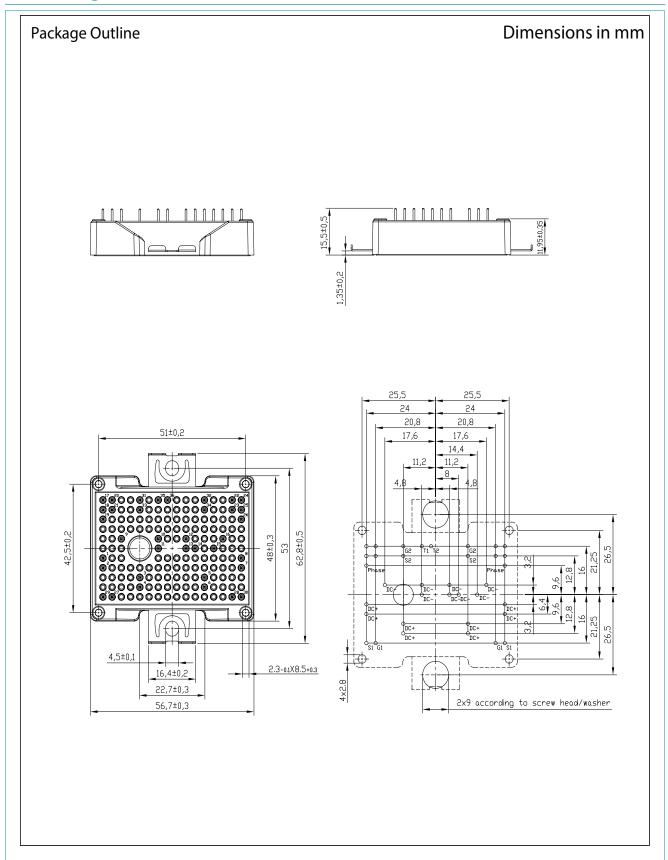
 $T_i = 25$ °C; $V_{DD} = 800$ V; $I_{DS} = 200$ A; $V_{GS} = -4$ V/18 V; Fig. 23. NTC thermistor resistance as a function of $L = 100 \mu H$

Fig. 22. Switching time as a function of external gate resistance



NTC temperature

11. Package outline



12. Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
Product [short] data sheet	Production	This document contains the product specification.

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WMSC006H12B2S

N-Channel Silicon Carbide MOSFET Module

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